



INFORMATION CITED BY APPLICANT(S) THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicant: T.-Y. Chang et al. Attorney Docket No. SIPT121256
Application No.: 10/601,709 Group Art Unit: ---
Filed: June 19, 2003 Examiner: ---
Title: INTEGRATED CIRCUIT DEVICE WITH A BUILT-IN DETECTING
CIRCUIT FOR DETECTING MAXIMUM MEMORY ACCESS TIME OF AN
EMBEDDED MEMORY

U.S. PATENT DOCUMENTS

| *Examiner Cite | Kind | Date | |
|---------------------------|------|--------------|-------------|
| Initials No. Document No. | Code | (mm/dd/yyyy) | Name |
| <u>CD</u> U1 6,424,583 | ✓ | 07/23/2002 | Sung et al. |

FOREIGN PATENT DOCUMENTS

| *Examiner Cite | Kind | Publication Date | Country | English |
|--------------------------|------|------------------|---------|----------------------|
| Initial No. Document No. | Code | (mm/dd/yyyy) | | Abstract Translation |
| | | | | Provided Provided |

None.

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

| *Examiner Cite | |
|----------------|--|
| Initial No. | |
| <u>CD</u> O1 | Sung and Wu, <i>A Method of Embedded Memory Access Time Measurement</i> , IEEE, 462-465 (2001) |
| <u>CD</u> O2 | Lee, Hsiao and Chang, <i>An Access Timing Measurement Unit of Embedded Memory</i> , IEEE, 104-109 (2002) |

Examiner

Date Considered

SON DINH

5/15/04

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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